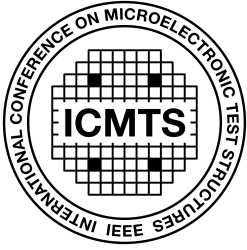


# ICMTS - The Measurement Conference



## 36<sup>th</sup> International Conference on Microelectronic Test Structures April 15-18, 2024, Edinburgh, Scotland

Looking for the best opportunity to present and discuss your ideas and results about test structures, measurements and characterisation? This is your chance! Join the 36th ICMTS conference.

A **Tutorial Short Course** will precede the main conference. Several of the best measurement, equipment design, and manufacturing experts, will participate in the **equipment exhibition** and presentations.

The conference will bring together designers and users of test structures to discuss recent developments and future directions, in a **one-track program**, with convivial breaks allowing attendees to discuss and exchange viewpoints and challenges.

A **Best Paper award** will be presented by the Technical Program Committee. The conference is co-sponsored by the **IEEE Electron Devices Society** and all accepted papers, if presented, will be submitted for possible inclusion on **IEEEExplore®**. **Original** papers are solicited presenting new developments in topics relevant to ICMTS, including but not limited to, **test structures, measurements, and results, in the following areas:**

- **Design**
  - Methodologies, Verification
  - Within-die circuits for process characterisation/monitoring
  - Design enablement – Characterisation and validation of digital and analog libraries
  - Devices and Circuit Modelling
- **Measurement techniques**
  - DC, AC and RF measurements: setup, test and analysis
  - Reliability test - including thermal stability, failure analysis etc.
  - Statistical analysis, variability, throughput increase, smart test strategies
  - Use of machine learning and AI in analysis of data sets - parameter extraction etc.
  - Wafer probing, within-die measurements, in-line metrology
  - Throughput, testing strategies, yield enhancement and process control tests
- **Applications**
  - Emerging memory technologies (single cell, arrays, and application in neural networks)
  - Emerging transistor technologies for digital/analog/power applications
  - Photonic devices - silicon integration, new displays (OLED,  $\mu$ -displays)
  - Flexible electronics and sensors (organic and inorganic materials)
  - M(N)EMS, actuators, sensors, PV cells and other emerging devices

The author's abstract submission consists of up to four pages in PDF format (font-embedded). The first page should include a **title**, a **50-word summary**, author name(s), full address, contact number and e-mail of the lead author, and any preference for oral or poster session presentation. The body of the abstract should consist of **one page of text** (800 to 1000 words) and **up to two pages of major figures and tables**.

The selection process will be based on the technical merit and will be highly weighted in favour of abstracts with *high test structure content*, giving a clear illustration of the test structure and *including measurements and data analysis*.

**The abstract submission deadline is October 27th, 2023.**

Abstracts can be submitted via the ICMTS 2024 website [www.icmts.net](http://www.icmts.net) using the "Abstract Submission" link the front page.

Notice of **paper acceptance** will be sent to the selected authors by **12th January 2024**, with instructions for the expanded manuscript preparation for the conference proceedings. The **deadline** for submission of the **final paper** will be **Early March, 2024 (TBC)**.

Please join the ICMTS group at <https://www.linkedin.com/groups/3804498>, if you have in interest all things test and measurement.

Details of the venue, hotel, registration, etc. will be posted when available at the ICMTS 2024 official web site.

**For further technical informatxion, please contact the technical program chair:**

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